A TEST PIN STRUCTURE

ABSTRACT

This invention discloses a test pin structure comprising a main body end (1), with a first elastic pin (2) and a second elastic pin (3) extending from the main body end (1) on the same side, wherein the first elastic pin (2) extends obliquely upward from one end of the main body end (1); the other end of the first elastic pin (2) is connected to a counteracting pin portion (5); and a needle tip (6) is vertically positioned at the other end of the counteracting pin portion (5); a pin (4) is vertically oriented downward at the other end of the second elastic pin (3); this invention reduces the sliding distance of the needle tip (6) by incorporating a counteracting pin portion (5) that moves in the opposite direction to the first elastic pin (2), and the pressure return force generated by the contact forces of the first elastic pin (2) and the counteracting pin portion (5) drives the needle tip (6) to be inserted into the chip. This way, when the pressure return force drives the needle tip (6) to be inserted into the chip, it avoids scratching the chip surface, and the magnitude of the pressure return force only affects the depth of insertion into the chip, without affecting the contact surface for testing; the left and right sliding of the needle tip is used to clean the contact surface of the needle tip.

(The most illustrative figure is FIG. 5)